# SIRENZA MICRODEVICES

Product Description

Sirenza Microdevices' SUF-6000 is a high gain broadband 2-stage amplifier covering 2-16 GHz for wideband communication and general purpose applications. This pHEMT FET-based amplifier uses a patented self-bias Darlington topology featuring a gain and temperature compensating active bias network that operates from a single 5V supply. Its compact size make it ideal for high-density multi-chip module applications.
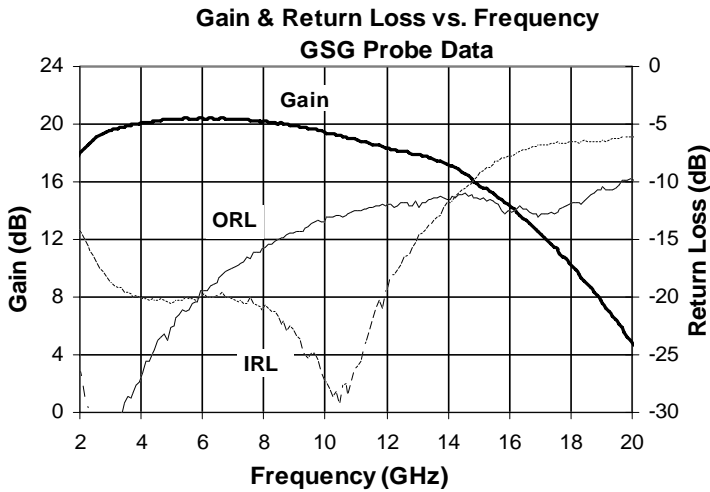
SUF-6000

2-16 GHz Broadband pHEMT Amplifier

Product Features

• **Broadband Performance**
• **High Gain = 17.4 dB @ 14 GHz**
• **P1dB = 12.0 dBm @ 14 GHz**
• **IP3 = 24.9 dBm @ 14 GHz**
• **5V Operation, No Dropping Resistor**
• **Low Gain Variation vs. Temperature**
• **Patented Thermal Design**
• **Patented Self-Bias Darlington Circuit**

Applications

• **Broadband Communications**
• **Test Instrumentation**
• **Military & Space**
• **LO and IF Mixer Applications**
• **High IP3 RF Driver Applications**

Gain & Return Loss vs. Frequency GSG Probe Data

Symbol	Parameters	Units	Frequency	Min.	Typ.	Max.
G_P	Small Signal Power Gain	dB	2 GHz		18.0	
			6 GHz		20.5	
			14 GHz		17.4	
P1dB	Output Power at 1dB Compression	dBm	2 GHz		13.0	
			6 GHz		14.0	
			14 GHz		12.0	
OIP3	Output Third Order Intercept Point	dBm	2 GHz		25.3	
			6 GHz		27.5	
			14 GHz		24.9	
NF	Noise Figure	dB	2 GHz		5.0	
			6 GHz		4.7	
			14 GHz		6.0	
IRL	Input Return Loss	dB	2 GHz		-14.2	
			6 GHz		-19.7	
			14 GHz		-12.1	
ORL	Output Return Loss	dB	2 GHz		-26.2	
			6 GHz		-19.4	
			14 GHz		-11.5	
Isol	Reverse Isolation	dB	2 GHz		-36.9	
			6 GHz		-34.4	
			14 GHz		-32.6	
V_D	Device Operating Voltage	V			5.0	
I_D	Device Operating Current	mA			107	
$\Delta G/\Delta T$	Device Gain Temperature Coefficient	dB/°C			TBD	
Rth, j-l	Thermal Resistance (junction-to-backside)	°C/W			TBD	

Test Conditions: V_D = 5.0V, I_D = 107mA, OIP3 Tone Spacing = 1MHz, Pout per tone = 0 dBm
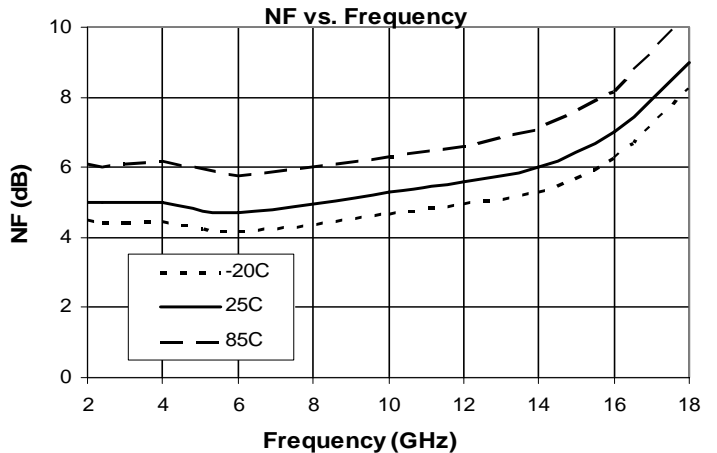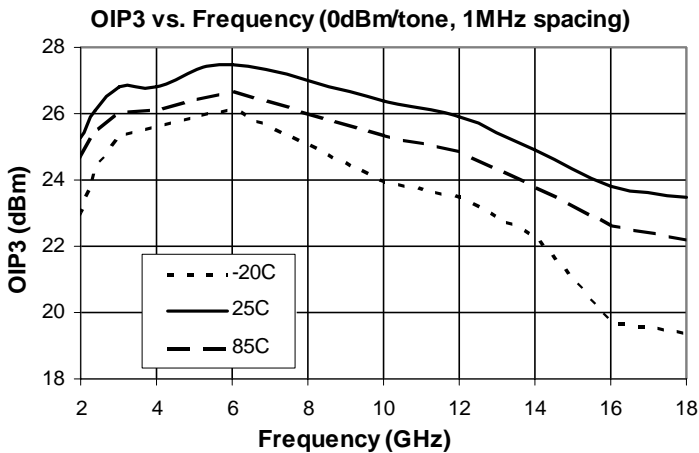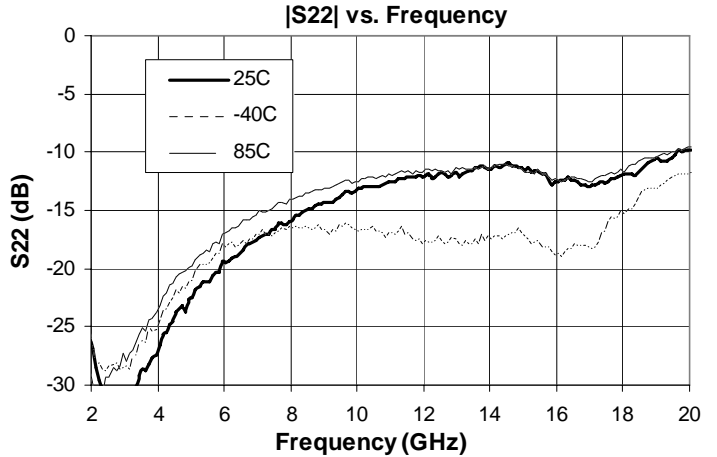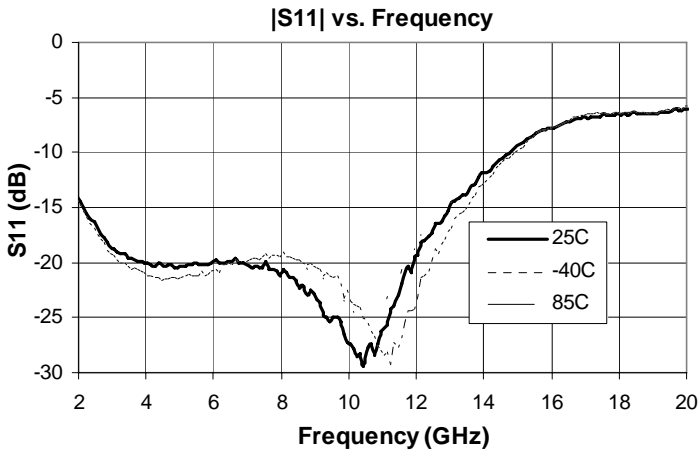$Z_S = Z_L$ = 50 Ohms, 25C, GSG Probe Data With Bias Tees

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EDS-105420 Rev A

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Typical Performance (GSG Probe Data)

|S21| vs. Frequency

P1dB vs. Frequency

|S11| vs. Frequency

|S22| vs. Frequency

OIP3 vs. Frequency (0dBm/tone, 1MHz spacing)

NF vs. Frequency

Typical Performance (GSG Probe Data)

Freq (GHz)	V_D (V)	Current (mA)	Gain (dB)	P1dB (dBm)	OIP3 (dBm)	S11 (dB)	S22 (dB)	NF (dB)
2	5	107	18.0	13.0	25.3	-14.2	-26.2	5.0
2.4	5	107	18.9	13.6	26.1	-16.2	-32.0	5.0
3	5	107	19.6	13.7	26.8	-18.6	-32.2	5.0
4	5	107	20.2	14.1	26.8	-20.0	-26.9	5.0
6	5	107	20.5	14.0	27.5	-19.7	-19.4	4.7
10	5	107	19.6	13.2	26.4	-26.3	-13.3	5.3
12	5	107	18.4	12.9	25.9	-19.9	-12.1	5.6
14	5	107	17.4	12.0	24.9	-12.1	-11.5	6.0
16	5	107	14.5	10.6	23.8	-7.9	-12.5	7.0

Test Conditions: GSG Probe Data With Bias Tees, OIP_3 Tone Spacing = 1MHz, Pout per tone = 0 dBm, 25°C

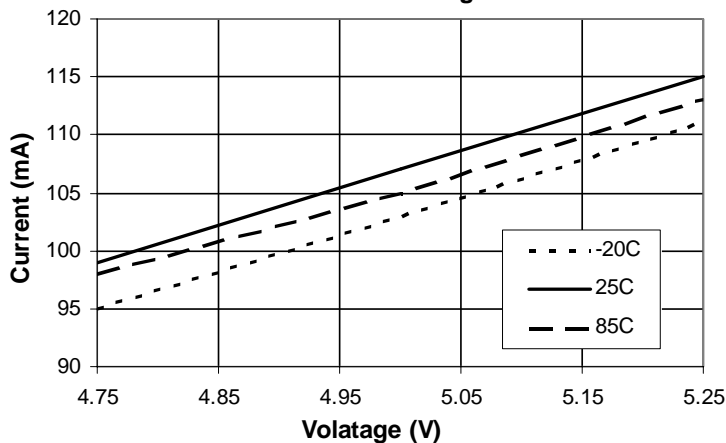| Parameter	Absolute Limit
Max Device Current (I_D)	163mA
Max Device Voltage (V_D)	5.5V
Max RF Input Power	10dBm
Max Dissipated Power	
Max Junction Temperature (T_J)	150C
Operating Temperature Range (T_L)	-40 to +85C
Max Storage Temp.	-65 to +150C

Operation of this device beyond any one of these limits may cause permanent damage. For reliable continuous operation, the device voltage and current must not exceed the maximum operating values specified in the table on page one.

Bias Conditions should also satisfy the following expression:

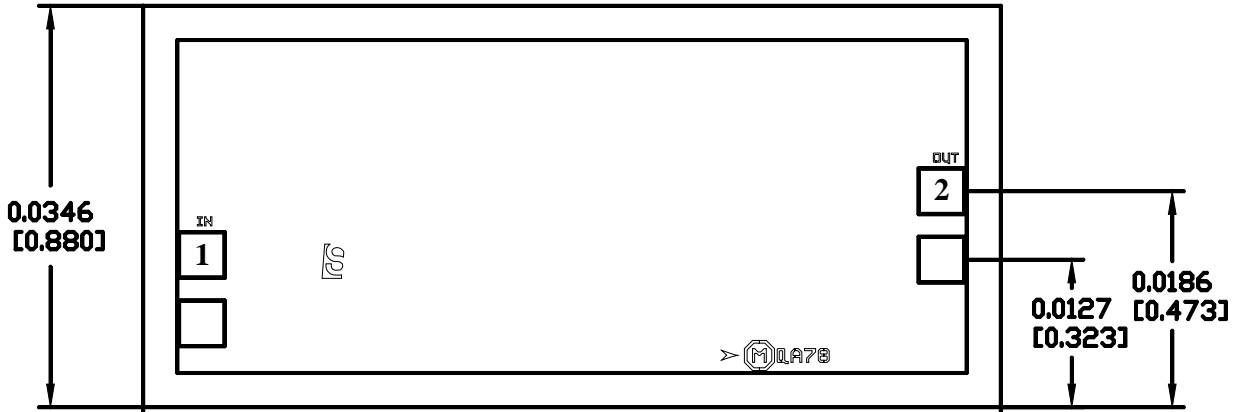$$I_D V_D < (T_J - T_L) / R_{TH, j-l} \quad T_L = \text{Backside of die}$$

ELECTROSTATIC SENSITIVE DEVICE
Appropriate precautions in handling, packaging and testing devices must be observed.

Current Variation vs. Temperature

Current vs. Voltage

Pad Description

Pad #	Function	Description
1	RF$_{IN}$	This pad is DC coupled and matched to 50 Ohms. An external DC block is required.
2	RF$_{OUT}$ / Bias	This pad is DC coupled and matched to 50 Ohms. Bias is applied through this pad.
Die Bottom	GND	Die bottom must be connected to RF/DC ground using silver-filled conductive epoxy.

Notes:
1. All Dimensions in Inches [Millimeters].
2. No connection required for unlabeled bond pads.
3. Die Thickness is 0.004 (0.100).
4. Typical bond pad is 0.004 (0.100) square.
5. Backside metalization: Gold.
6. Backside is Ground.
7. Bond pad metalization: Gold.

Device Assembly